

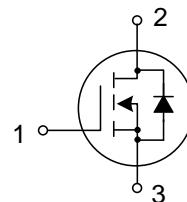
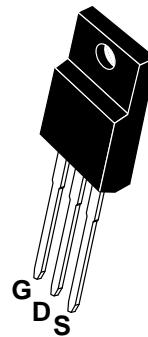
PIN Connection TO-220F
General Description

FIR4N60FG is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved planar stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are widely used in AC-DC power suppliers, DC DC converters and H-bridge PWM motor drivers.

Features

- 4A,600V, $R_{DS(on)}$ _(typ)=2.0Ω@ V_{GS} =10V
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability


Marking Diagram


Y = Year
 A = Assembly Location
 WW = Work Week
 FIR4N60F = Specific Device Code

Absolute Maximum Ratings (Ta = 25°C unless otherwise noted; reference only)

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	600	V
Gate-Source Voltage	V_{GS}	±30	V
Drain Current $T_C=25^\circ\text{C}$	I_D	4.0	A
$T_C=100^\circ\text{C}$	I_D	2.5	
Drain Current Pulsed	I_{DM}	16	A
Power Dissipation($T_C=25^\circ\text{C}$) -Derate above 25°C	P_D	33	W
	P_D	0.26	W/°C
Single Pulsed Avalanche Energy(Note 1)	E_{AS}	217	mJ
Operation Junction Temperature Range	T_J	-55~+150	°C
Storage Temperature Range	T_{stg}	-55~+150	°C

Thermal Characteristics

Characteristics	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.61	°C/W
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	110	°C/W

Electrical Characteristics ($T_a = 25^\circ C$ unless otherwise noted; reference only)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	B_{VDS}	25 °C, $V_{GS}=0V$, $I_D=250\mu A$	600	--	--	V
		125 °C, $V_{GS}=0V$, $I_D=250\mu A$	600	--	--	V
Drain-Source Leakage Current	I_{DSS}	25 °C, $V_{DS}=800V$, $V_{GS}=0V$	--	--	10	uA
		125 °C, $V_{DS}=800V$, $V_{GS}=0V$	--	--	50	uA
		150 °C, $V_{DS}=800V$, $V_{GS}=0V$	--	--	100	uA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 30V$, $V_{DS}=0V$	--	--	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}= V_{DS}$, $I_D=250\mu A$	2.0	--	4.0	V
Static Drain- Source On State Resistance	$R_{DS(on)}$	$V_{GS}=10V$, $I_D=2A$	--	2.0	2.4	Ω
Input Capacitance	C_{iss}	$V_{DS}=25V$, $V_{GS}=0V$, $f=1.0MHz$	--	509.00	--	pF
Output Capacitance	C_{oss}		--	57.57	--	
Reverse Transfer Capacitance	C_{rss}		--	2.59	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=300V$, $I_D=4A$, $R_G=25\Omega$	--	14.20	--	ns
Turn-on Rise Time	t_r		--	27.73	--	
Turn-off Delay Time	$t_{d(off)}$		--	34.67	--	
Turn-off Fall Time	t_f		--	28.53	--	
Total Gate Charge	Q_g	$V_{DS}=480V$, $I_D=4A$, $V_{GS}=10V$	--	11.88	--	nC
Gate-Source Charge	Q_{gs}		--	3.33	--	
Gate-Drain Charge	Q_{gd}		--	4.90	--	

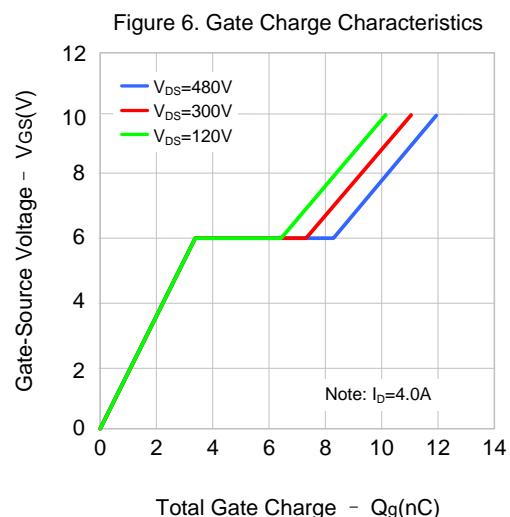
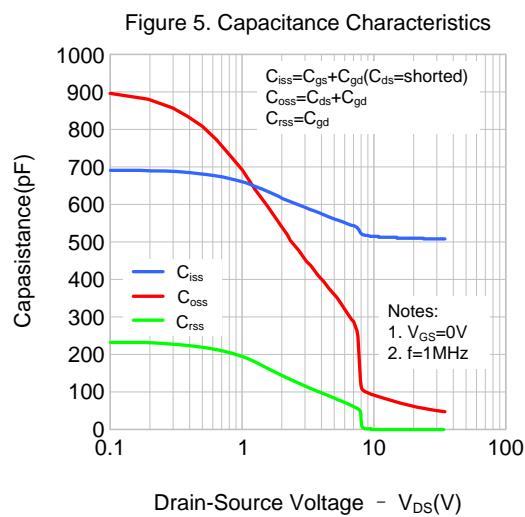
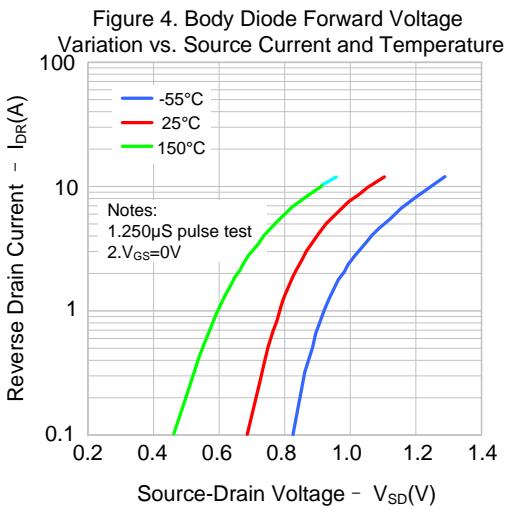
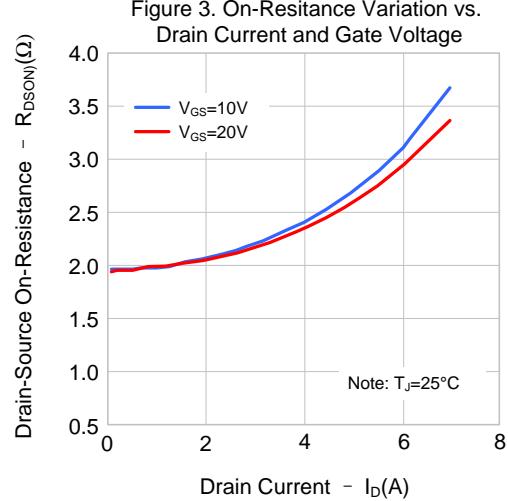
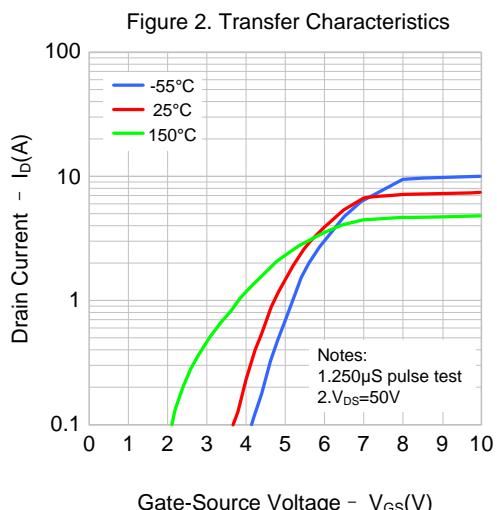
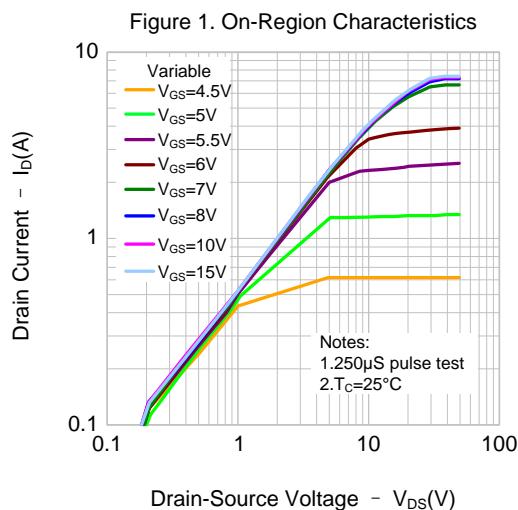
Source-Drain Diode Ratings And Characteristics

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_s	Integral Reverse P-N Junction Diode in the MOSFET	--	--	4.0	A
Pulsed Source Current	I_{SM}		--	--	16	
Diode Forward Voltage	V_{SD}	$I_S=4.0A$, $V_{GS}=0V$	--	--	1.4	V
Reverse Recovery Time	T_{rr}	$I_S=4.0A$, $V_{GS}=0V$,	--	408	--	ns
Reverse Recovery Charge	Q_{rr}	$dI_F/dt=100A/\mu s$ (Note 2)	--	1.98	--	μC

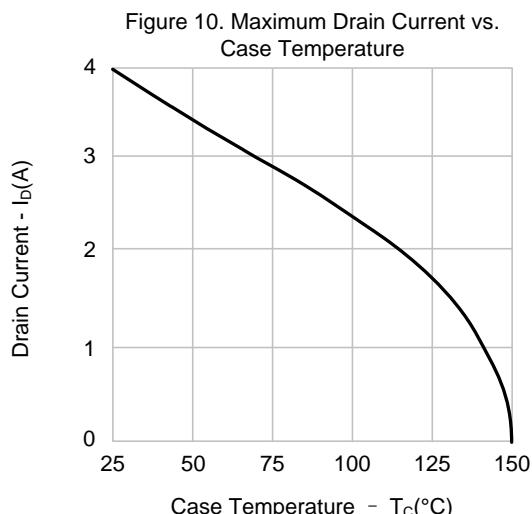
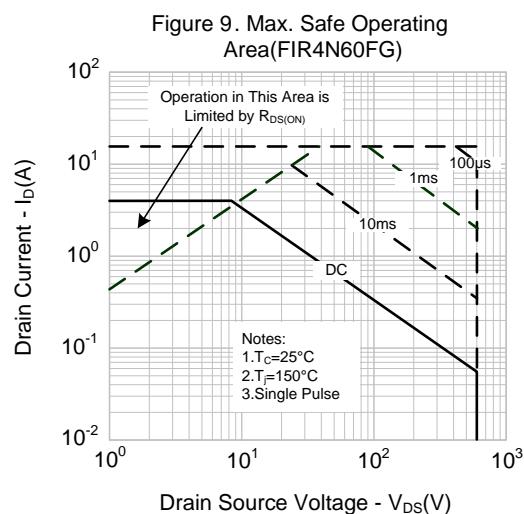
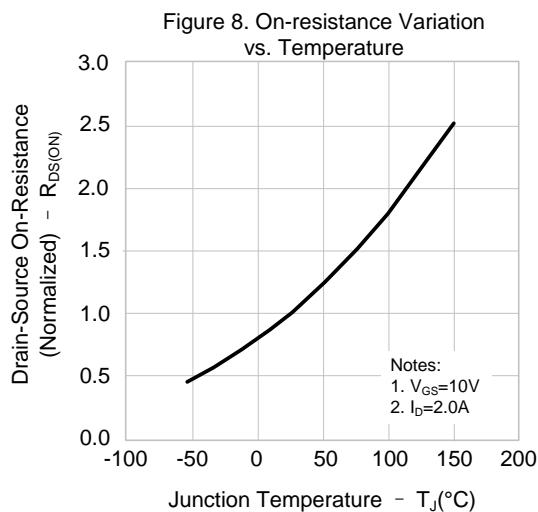
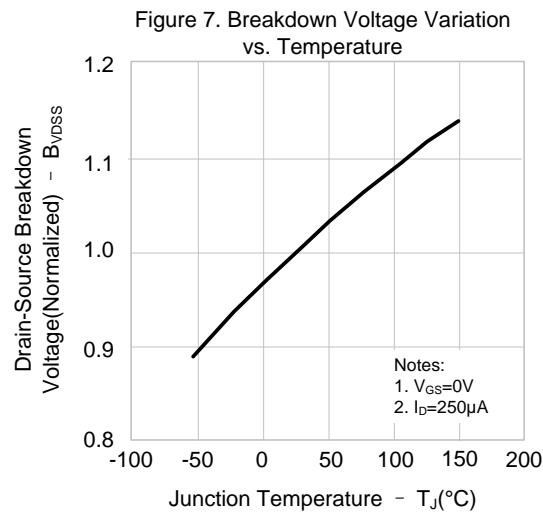
Notes:

1. $L=30mH$, $I_{AS}=3.45A$, $V_{DD}=100V$, $R_G=25\Omega$, starting $T_J=25^\circ C$;
2. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;
3. Essentially independent of operating temperature.

Typical Characteristics

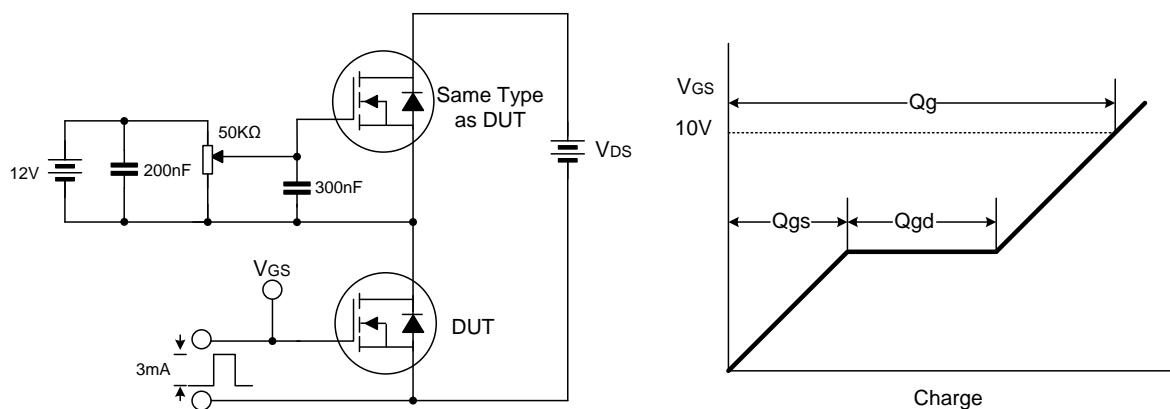


Typical Characteristics(Continued)

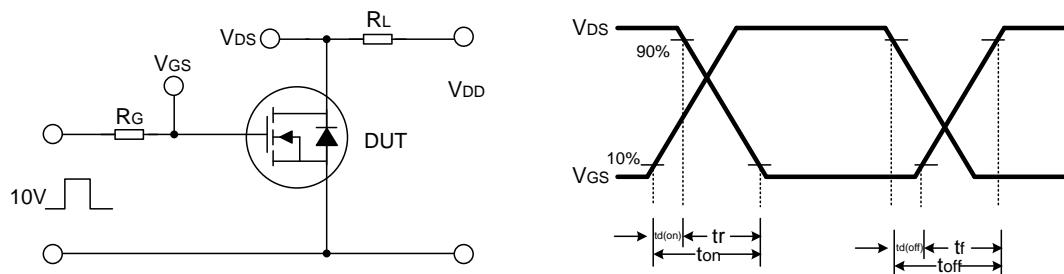


Typical Test Circuit

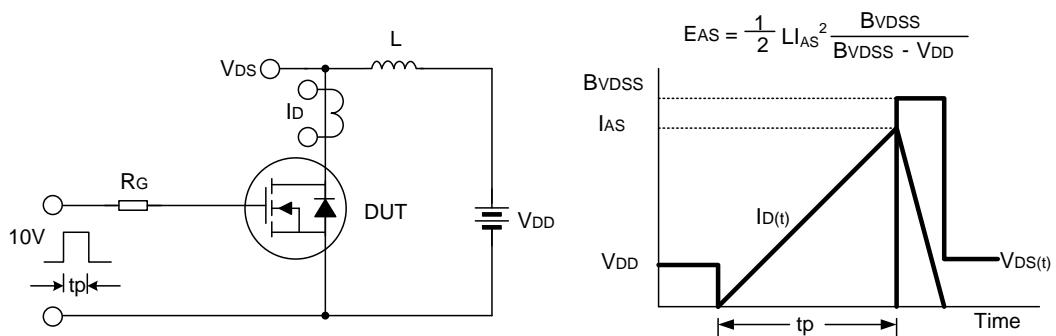
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform

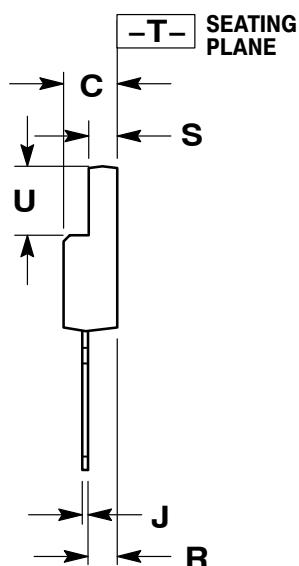
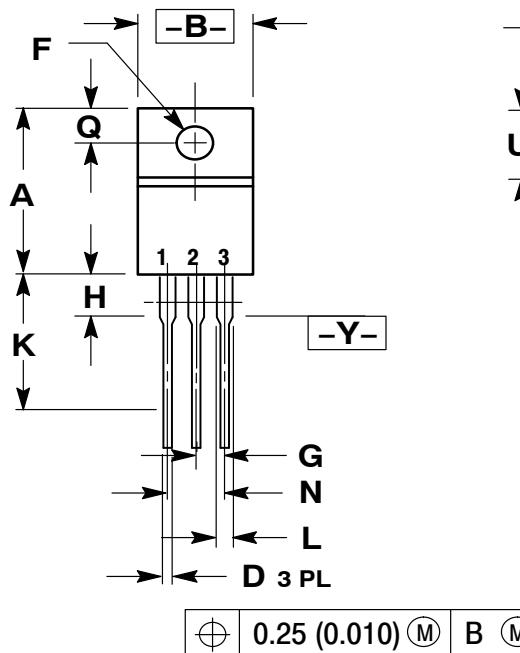


Unclamped Inductive Switching Test Circuit & Waveform



Package Dimensions

TO-220F



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH
3. 221D-01 THRU 221D-02 OBSOLETE, NEW STANDARD 221D-03.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.617	0.635	15.67	16.12
B	0.392	0.419	9.96	10.63
C	0.177	0.193	4.50	4.90
D	0.024	0.039	0.60	1.00
F	0.116	0.129	2.95	3.28
G	0.100 BSC		2.54 BSC	
H	0.118	0.135	3.00	3.43
J	0.018	0.025	0.45	0.63
K	0.503	0.541	12.78	13.73
L	0.048	0.058	1.23	1.47
N	0.200 BSC		5.08 BSC	
Q	0.122	0.138	3.10	3.50
R	0.099	0.117	2.51	2.96
S	0.092	0.113	2.34	2.87
U	0.239	0.271	6.06	6.88

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